



Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/632,466	MILAN ET AL.	
	Examiner	Art Unit	
	Kim T. Huynh	2112	

ISSUE CLASSIFICATION									
ORIGINAL				CROSS REFERENCE(S)					
CLASS	SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
710	100			455	226				
INTERNATIONAL CLASSIFICATION									
G	0	G	F						
				13100					
				/					
				/					
				/					
				/					
Kim T. Huynh 10/26/05 (Assistant Examiner) (Date)				 REHANA PERVEEN SUPERVISORY PATENT EXAMINER (Primary Examiner) (Date) 10/26/05				Total Claims Allowed: 9 O.G. Print Claim(s) 35 O.G. Print Fig. 2	

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant				<input type="checkbox"/> CPA				<input type="checkbox"/> T.D.				<input type="checkbox"/> R.1.47			
Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original		
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